Search Notes			

Application/Control No.	Applicant(s)/Patent unde Reexamination	er
10/576,784	VAN DER SCHAAF ET AL.	
Examiner	Art Unit	
Karen Cheng	1626	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
STN Structure Search (see attached)	3/9/2007	кс
EAST Search (see attached)	3/9/2007	кс
Inventor Name Search (PALM)	3/12/2007	Ke